# **Power MOSFET**

# 30 V, 29 A, Single N-Channel, SO-8 Flat Lead

#### **Features**

- Low R<sub>DS(on)</sub>
- Optimized Gate Charge
- Low Inductance SO-8 Package
- This is a Pb-Free Device

#### **Applications**

- Notebooks, Graphics Cards
- DC-DC Converters
- Synchronous Rectification

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Paramet	Symbol	Value	Unit			
Drain-to-Source Voltage			V <sub>DSS</sub>	30	V	
Gate-to-Source Voltage			$V_{GS}$	20	V	
Continuous Drain Current	Steady T <sub>A</sub> = 25°C		I <sub>D</sub>	17	Α	
(Note 1)	State	State $T_A = 85^{\circ}C$		12		
	t ≤10 s	$T_A = 25^{\circ}C$		29		
Power Dissipation (Note 1)	Steady State $T_A = 25^{\circ}C$		P <sub>D</sub>	2.2	W	
	t ≤10 s			6.6		
Continuous Drain Current	0	$T_A = 25^{\circ}C$	ΙD	11	Α	
(Note 2)	Steady State	T <sub>A</sub> = 85°C		8.0		
Power Dissipation (Note 2)		$T_A = 25^{\circ}C$	$P_{D}$	0.9	W	
Pulsed Drain Current	t <sub>p</sub> =	10 μs	I <sub>DM</sub>	88	Α	
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	–55 to 150	°C	
Source Current (Body Diode)			Is	6.5	Α	
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_{PK}$ = 29 A, L = 1 mH, $R_G$ = 25 $\Omega$ )			E <sub>AS</sub>	430	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C	

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	56.2	°C/W
Junction-to-Ambient - t ≤ 10 s (Note 1)	$R_{\theta JA}$	19	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	141.1	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

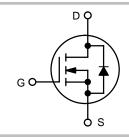
- Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
- Surface mounted on FR4 board using the minimum recommended pad size (Cu area = 1.0 in sq).



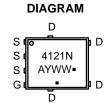
## ON Semiconductor®

#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX (Note 1)
30 V	4.0 mΩ @ 10 V	29 A
50 1	5.5 mΩ @ 4.5 V	2374







**MARKING** 

4121N = Specific Device Code A = Assembly Location Y = Year

WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4121NT1G	SO-8 FL (Pb-Free)	1500 Tape & Reel
NTMFS4121NT3G	SO-8 FL (Pb-Free)	5000 Tape & Reel

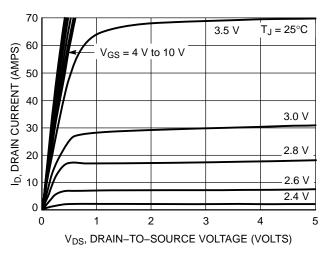
- †For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.
- \*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•		•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				21		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V 0.V.V 04.V	T <sub>J</sub> = 25°C			1.0	μΑ
		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> =	= 20 V			100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 3$	250 μΑ	1.0		2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.4		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> =	= 24 A		4.2	5.25	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> =	= 21 A		5.5	7.0	
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub> =	= 24 A		20		S
CHARGES, CAPACITANCES AND GATE R	ESISTANCE				•	•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 24 V			2700		pF
Output Capacitance	C <sub>OSS</sub>				480		
Reverse Transfer Capacitance	C <sub>RSS</sub>				290		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 21 A			24	40	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				3.0		
Gate-to-Source Charge	$Q_{GS}$				7.3		
Gate-to-Drain Charge	$Q_{GD}$				10.2		
Gate Resistance	$R_{G}$				2.0		Ω
SWITCHING CHARACTERISTICS, V <sub>GS</sub> = 4.	5 V (Note 4)						
Turn-On Delay Time	t <sub>d(ON)</sub>				16		ns
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS}$	= 15 V.		29		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 1.0 \text{ A}, R_L = 15 \Omega, R_G = 3.0 \Omega$			32		
Fall Time	t <sub>f</sub>				31		
DRAIN-SOURCE DIODE CHARACTERISTI	cs				•		•
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = 0 \text{ V, } I_S = 6.0 \text{ A}$ $T_J = 25^{\circ}\text{C}$ $T_J = 125^{\circ}\text{C}$	$T_J = 25^{\circ}C$		0.8	1.0	V
				0.6			
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 6.0 \text{ A}$			34		ns
Charge Time	ta				18		
Discharge Time	t <sub>b</sub>				16		
Reverse Recovery Charge	Q <sub>RR</sub>				25.4		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

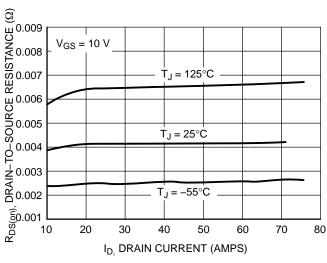
#### TYPICAL PERFORMANCE CURVES



70  $V_{DS} \ge 10 \text{ V}$ 60 ID, DRAIN CURRENT (AMPS) 50 40 30  $T_J = 125^{\circ}C$ 20  $T_J = 25^{\circ}C$ 10  $T_1 = -55^{\circ}C$ 0 0 5 V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



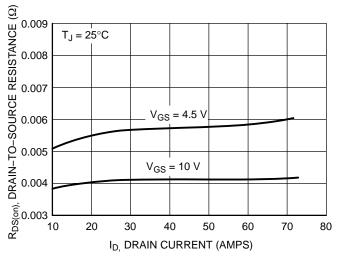
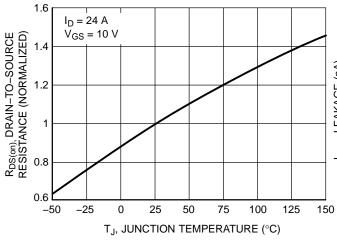


Figure 3. On–Resistance vs. Drain Current and Temperature

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



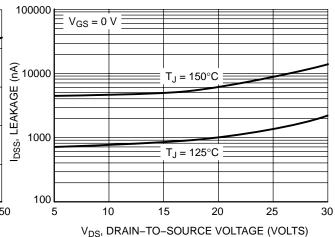


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL PERFORMANCE CURVES**

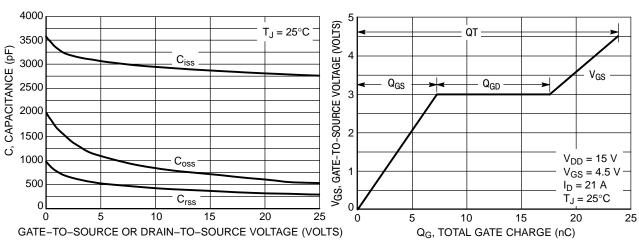


Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

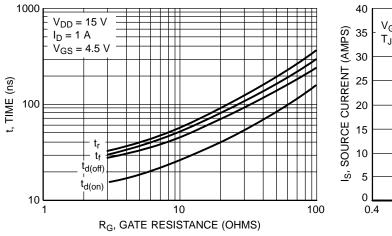


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

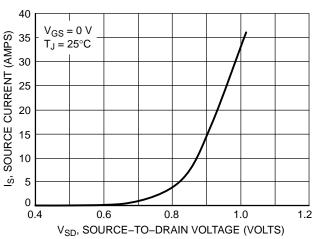


Figure 10. Diode Forward Voltage vs. Current

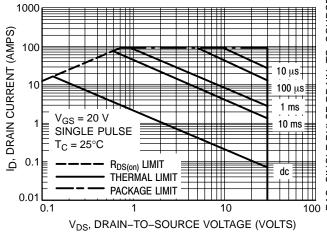


Figure 11. Maximum Rated Forward Biased Safe Operating Area

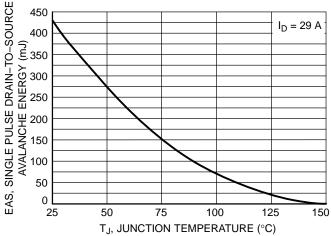


Figure 12. Maximum Avalanche Energy vs Starting Junction Temperature

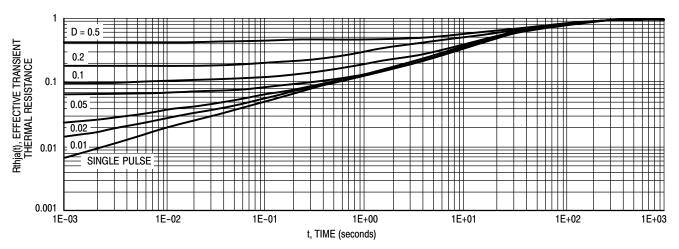
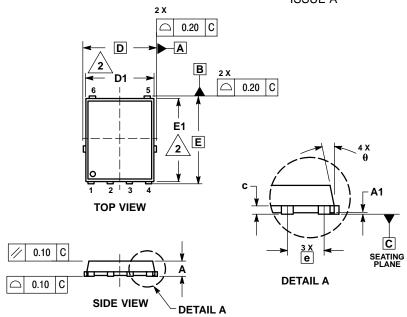


Figure 13. Thermal Response

#### PACKAGE DIMENSIONS

#### SO-8 FLAT LEAD CASE 488AA-01 **ISSUE A**

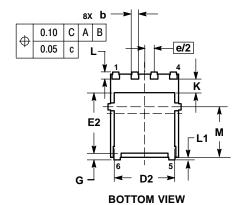


- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION D1 AND E1 DO NOT INCLUDE
  MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	0.99	1.20		
A1	0.00		0.05		
b	0.33	0.41	0.51		
С	0.23	0.28	0.33		
D		5.15 BSC			
D1	4.50	4.90	5.10		
D2	3.50		4.22		
E	6.15 BSC				
E1	5.50	5.80	6.10		
E2	3.45		4.30		
е		1.27 BSC			
G	0.51	0.61	0.71		
K	0.51				
L	0.51	0.61	0.71		
L1	0.05	0.17	0.20		
М	3.00	3.40	3.80		
θ	0 °		12 °		

STYLE 1: PIN 1. SOURCE 2. SOURCE 3. SOURCE

- 4. GATE
- 5. DRAIN



ON Semiconductor and un are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 61312, Phoenix, Arizona 85082-1312 USA Phone: 480-829-7710 or 800-344-3860 Toll Free USA/Canada Fax: 480-829-7709 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free

Japan: ON Semiconductor, Japan Customer Focus Center 2-9-1 Kamimeguro, Meguro-ku, Tokyo, Japan 153-0051 Phone: 81-3-5773-3850

ON Semiconductor Website: http://onsemi.com

Order Literature: http://www.onsemi.com/litorder

For additional information, please contact your local Sales Representative.